열처리된 CuGaSe2 단결정 박막의 점결함연구 A study on point defect for thermal annealedCuGaSe2 single crystal thin film

이상열, <u>홍광준</u> 조선대학교 물리학과 (syleeb@mail.chosun.ac.kr)

A stoichiometric mixture of evaporating materials for CuGaSe2 single crystal thin films was prepared from horizontal electric furnace. Using extrapolation method of X-ray diffraction patterns for the polycrystal CuGaSe2, it was found tetragonal structure whose lattice constant a and c_0 were 5.615 Å and 11.025 Å, respectively. To obtain the single crystal thin films, CuGaSe2 mixed crystal was deposited on thoroughly etched semi-insulating GaAs(100) substrate by the hot wall epitaxy (HWE) system. The source and substrate temperatures were 610°C and 450°C, respectively. The crystalline structure of the single crystal thin films was investigated by the photoluminescence and double crystal X-ray diffraction (DCXD). The carrier density and mobility of CuGaSe2 single crystal thin films measured with Hall effect by van der Pauw method are 5.01×10¹⁷ cm⁻³ and 245 cm²/V·s at 293K, respectively. The temperature dependence of the energy band gap of the CuGaSe2 obtained from the absorption spectra was well described by the Varshni's relation, Eg(T) = 1.7998 eV - $(8.7489 \times 10^{-4} \text{ eV/K})\text{T}^2/\text{(T + 335)}$ K). After the as-grown CuGaSe2 single crystal thin films was annealed in Cu-, Se-, and Gaatmospheres, the origin of point defects of CuGaSe2 single crystal thin films has been investigated by the photoluminescence(PL) at 10 K. The native defects of V_{CI}, V_S, Cu_m, and Sein obtained by PL measurements were classified as a donors or acceptors type. And we concluded that the heat-treatment in the Cu-atmosphere converted CuGaSe2 single crystal thin films to an optical n-type. Also, we confirmed that Ga in CuGaSe2/GaAs did not form the native defects because Ga in CuGaSe2 single crystal thin films existed in the form of stable bonds.